

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10573155	MAEKAWA ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Thien F Tran	2895

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
438	406, 455, 458	02/24/2009	TT

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Search history printout	02/24/2009	TT
Search history printout	02/25/2009	TT
Search history printout	08/11/2009	TT
Search history printout	09/09/2009	TT
Search history printout	01/14/2010	TT

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
All		08/11/2009	TT
All		09/09/2009	TT
All		01/14/2010	TT

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